arXiv:cond-mat/0611153v3 [cond-mat.mes-hall] 28 May 2007 Q¹(T) sible applications.

D issipation due to two-level system s in nano-m echanical devices

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A bstract. -W e analyze the dissipation of the vibrations of nano-m echanical devices. W e show that the coupling between exural m odes and two-level system s leads to sub-ohm ic dissipation. The inverse quality factor of the exural m odes of low frequencies depends on temperature as $Q^{-1}(T) = Q_0 + CT^{1=3}$, providing a quantitative description of the experimental data.

Introduction. { Nano-electro-mechanical devices [1, 2] (NEM S) are system s with great potential for applied physics and engineering because of their extrem e sensitivity, as probes, to their environment [3{9]. Furthermore, because of their small size and large surface to volume ratio, these systems are in the crossover region between classical and quantum behavior, and hence of great theoretical interest. Thus, the study of the sources of noise and dissipation in these system s has attracted a great deal of attention [10{18]. O ne of the common realizations of nano-mechanical resonators is a rigid beam of nanoscopic dimensions which vibrates at GHz frequencies [19,20]. The damping of these oscillations has been a subject of intense investigation [10,13,15,16], as it sets a limit to their possible applications.

The damping of a low frequency oscillation in a NEM S com es from the coupling of this mode to other low energy degrees of freedom . Experim ents suggest that surfaces of nano-m echanical resonators resemble am orphous bulk systems [21], with a high density of defects, playing a major role as a source of dissipation [22]. In am orphous solids, disorder and in purities lead to the existence of anharm onic excitations, which can be modeled as a degree of freedom tunneling between two potential wells [23]. A simpler two-level system (TLS) description arises at low tem peratures, when only the two lowest eigenstates have to be considered. Some properties of the distribution of TLSs in terms of their parameters (bias, $\frac{z}{0}$, and tunneling rate, $\frac{x}{0}$) can be inferred from experiments [24], and they are considered to be the main source of dam ping of acousticalm odes in disordered insulating solids [24{27].

In this work, we study mostly a rigid beam geometry, sketched in g. [1], and analyze the dissipation processes for low energy exural modes due to the presence of e ective TLSs at its surface. The generalization to dissipation of torsional modes is straightforward and will be given elsewhere. Once a given mode is externally excited, the TLSs living at the surface of the beam, which are coupled to this mode, will absorb part of its energy. But as the TLSs are also coupled to the rest of vibrational modes of the beam, they will release most of this energy to them. Thus the TLSs give rise to an indirect coupling between the externally excited mode and the rest of modes. For the experimentally relevant case of low am plitudes of vibration this coupling prevails over the usual anharm onic coupling.

This energy ow process will be described in two stages:

i) From the point of view of a given TLS, its coupling to the vibrationalm odes of the beam, which can be seen as an external bath, alters its dynam ics and enables it to absorb and em it energy in a broad range of frequencies. In particular, the presence of exural modes leads to the possibility of qualitative changes in the dynam ics of the TLSs, as the form er constitute a sub-ohm ic environm ent [28,29] for the TLSs. This is a consequence of the quadratic dispersion relation characteristic of exural modes, which results in an enhancem ent of the density of low frequency modes.

ii) Coming back to the externally excited vibrational mode whose damping we want to compute, the TLSs, dressed by all the vibrationalm odes of the structure, constitute the dissipative environment for the mode. This



Fig. 1: Sketch of the NEM S: a) Doubly clamped beam, suspended by both ends; b) C antilever, with one free end. The device is characterized by its width (w), thickness (t), and length, (L), where w t L.

involves TLSs that are nearly resonant with the mode under consideration but also o resonance TLSs since the strong phonon/TLS coupling provides each TLS spectral function with tails far from resonances. In many NEMS experiments, the exuralmodes studied are highly excited, either because of an external driving mechanism, or because the tem perature is much higher than the frequency of the mode. As a given TLS can absorb and em it over a broad range of energies, due to the incoherent tails in its spectrum (see below), these processes allow for the transfer of energy from a highly excited low frequency exural m ode to other m odes with higher frequencies.

D issipative mechanisms other than TLSs, which have been extensively studied elsewhere [30{32], are not considered here.

TLSs coupled to low dim ensional vibrations. { The TLSs are mainly coupled to the strain induced by phonons. It is assumed that the main e ect of the strain is to modify the energy splitting between the TLSs energy levels [33]. The Ham iltonian of a given TLS is characterized by a bias, ${}^{z}_{0}$, and the tunneling rate, ${}^{x}_{0}$ (we use units such that $h = 1 = k_B$, and om it the part of the Ham iltonian describing free vibrations):

$$H = {}_{0 x}^{x} + {}_{0 z}^{z} + {}_{z}F(@_{i}u_{j})$$
(1)

where $Q_i u_j$ is a component of the deformation gradient matrix, and F is an arbitrary function. Changing basis to the energy eigenstates of the TLS, eq.(1) becom es $H = 0_{z} + [(0_{z} = 0)_{x} + (0_{z} = 0)_{z}]F(0_{i}u_{j}).$ 0 = $(\frac{x}{0})^2 + (\frac{z}{0})^2$ is the splitting of the TLS. D issipation is dominated by slightly biased TLSs for whom z 0 $_{0}$, so the last term can be ignored. A further expansion of F to lowest order in the displacement, together with a =4 rotation of the eigenbasis, leads to: $H = 0_x + (x_0^x = 0)_z Q_i u_j$, where is the coupling constant (with dim ensions of energy).

to the coupling to the operator $_{z}$ of each TLS. Hence, the the previous results, we not the spectral function J (!) absorption properties of each TLS can be characterized by plotted in Fig.[2].

the spectral function:

A (!)
$$\frac{1}{2}$$
 $\frac{1}{2}$ $\frac{1}{2}$

where ini is an excited state of the total system TLS plus vibrations. The linearization of the coupling im plies that the interaction between a given TLS and the vibrations $z_k k b_k^{Y} + b_k$. can be written as H_{int}

We also de ne a spectral function that determines the damping induced by phonons on the TLS: J (!)

_kj_kj́ (! $!_k$) where $!_k$ is the energy of mode k. The vibrationalm odes of a beam with xed ends have a discrete spectrum, but we will approximate them by a continuous distribution. This approximation will hold as long as many vibrational modes become therm ally populated, $h!_{\,{\tt fund}}$, where $!_{\,{\tt fund}}$ is the frequency of the lowest kТ mode. The condition is fulled in current experimental setups.

A coustic modes of a nanoscopic beam. Using continuum elasticity theory [34], a one-dim ensional (1D) rod has com pression and twisting modes, with a linear relation between frequency and momentum, and bending, or exural, modes, where the frequency depends quadratically on m om entum. W e will consider a rod of length L, width w and thickness t, see Fig.[1]. We describe next the spectral function which describes how the modes of the rod absorb energy in di erent energy ranges.

The compression and twisting modes lead to an ohm ic spectral function for ! 2 c=R (R being a typical transversaldimension of the rod and c the sound velocity), when the rod is e ectively 1D. In term softhe Young m odulus of the m aterial, E , and the m ass density, , we get: $J_{com p}$ (!) = $_{c}$ j! j, where,

$$x_{2} = (x_{0} = x_{0})^{2} (2^{2} \text{ tw})^{1} (E =)^{3=2}$$
 : (3)

The twisting modes are de ned by the torsional rigidity, $C = t^3 w = 3$ (is a Lande coe cient), and I = 1 $dSx^2 =$ $t^3 w = 12$ (where S is the cross-section). The corresponding spectral function is given by: J_{torsion} (!) = tj!j, where

$$t = C (_{0} = _{0})^{2} (8 ^{2} tw I) ^{1} (I=C)^{3=2}$$
: (4)

The analysis of the exural (bending) modes diers substantially from the other ones, because they correspond to two elds $_{j}(z;!)$ (j = x;y) that satisfy [34]: $E I_j Q_z^4 = tw !_j^2 ; where, for the system considered$ here, $I_j = t^3 w = 12 \cdot p^T$ he norm alm odes have a quadratic dispersion $!_j(k) = \frac{T_j}{E_j} \frac{1}{I_j} = (tw) k^2$. Their corresponding spectral function is sub-ohm ic [28], $J_{ex}(!) = \int_{b}^{P} \frac{1}{CO} \frac{1}{CO} \frac{1}{CO}$ with,

$${}_{\rm b}^{\rm p} \overline{!}_{\rm co} = 0.3 \frac{2}{t^{3=2} w} \frac{(1+)(1-2)}{E(3-5)} \frac{1}{E}^{1=4};$$
 (5)

where is Poisson's ratio and $!_{co}$ ' $p = I_v = (tw)(2 = t)^2$ The main interaction between phonons and TLSs is due is the high energy cut-o of the bending modes. Collecting



Fig. 2: Sketch of the contributions to the spectral function which determ ines the dynam ics of the TLS.

Dynamics of the TLSs. { We are interested in the TLSs that a ect most the low-energy exural vibrations. Hence, we focus on the TLSs whose tunneling amplitudes lie in the region where the damping is subohm ic. We de ne r as the tunneling am plitude of a given TLS, including the renorm alization due to the high energy acoustic m odes. W e assum e, as in the case of glasses, that the distribution of these TLSs is given by [24,25] g(r; z) = P = r. The sub-ohm ic coupling, eq.(5), leads to a renorm alization of r:

$$ren = rexpf \qquad b \frac{p}{!co} \frac{g}{s} \frac{g}{d!} J(!) = !^{2}g \qquad (6)$$

This equation has no solutions other than $_{ren} = 0$ if $_{\rm b}^2!_{\rm co}$, so that the tunneling am plitude of the low r

energy TLSs is strongly suppressed [28,29,35,36]. The remaining TLSs experience a shift and a broadening of the spectral function function A (!), de ned in eq.(2). In addition, A (!) acquires a low energy tail, which, at zero tem perature, is [37]:

A (!) /
$$b \frac{p_{\frac{1}{\cos !}}}{\frac{2}{\operatorname{ren}}}$$
 ! ren (7)

There is also a high energy part, A(!) / $p_{b} = \frac{p_{co}}{1 co} \frac{2}{ren} \frac{1}{ren} \frac{7}{ren}$, for ! ren. The main features of A (!) are shown in g. [3]. Finally, we obtain the width of the resonant peak, $p(\underline{ren})$, using Ferm i's golden rule, $(_{ren}) = 16 \frac{p}{b} \frac{p}{!co} \frac{p}{ren}$. This description is valid for wavelengths such that, 1=L k 1=m ax(w;t).

The value of z is not renorm alized by the phonons, so that the TLS cannot exchange energy with the environment at frequencies lower that z_z . In the following, we will consider only TLSs with $z^{<}$ ren .

The total absorption rate by the ensemble of dressed TLSs present in the beam, A_{tot} (!), is obtained sum ming over g(r; z) the values of A(!), eq.(2), of each dressed TLS. In am orphous insulators, like am orphous silica, there are TLSs with r up to about ! = 5 K [24]. The upper cut-o of the distribution is usually larger than the frequencies of the exural modes of interest, $!_{co} < !$. Integrating over $\ensuremath{_z}$ and $\ensuremath{_{\text{ren}}}$, we nd that the density of TLSs per unit volume and unit energy available for direct (resonant) excitation processes is given by P, in times, in systems where the oscillator is driven strongly



Fig. 3: Sketch of the spectral function of a TLS coupled to a sub-ohm ic bath. Dashed line shows the o -resonant contribution. Dot-dashed line shows the main broadened peak. For com parison, the thick vertical line shows the spectral function of a non-interacting TLS.

agreem ent with the known result that TLSs in am orphous systems give rise to a nite density of states at low energies [25]. In addition, we nd a contribution coming from the non-resonant part of the spectral function of each TLS, ${\rm A}_{\rm tot}^{\rm off res}$ (!) 2P $_{\rm b}$! $_{\rm co}$ =!. The divergence as ! ! 0 arises from the $\frac{2}{\text{ren}}$ dependence of A (!), eq.(7).

D issipation due to the TLSs. { We assume that the externally excited exural mode of interest, $(k_0;!_0)$, is linearly coupled, with the coupling constant shown in the derivation of the ham iltonian H , $\begin{pmatrix} x \\ 0 \end{pmatrix} = \begin{pmatrix} x \\ 0 \end{pmatrix}$, to a continuum of excitations whose spectral strength, Atot (!), is given by the sum mation over all TLSs of the function A (!) calculated for each one. The ratio $\begin{pmatrix} x \\ 0 \end{pmatrix} = 0$ can be approximated as 1, due to the negligible role played by strongly biased TLSs.

The transition rate of the mode k₀ occupied by n phonons to the mode with n 1 is calculated from Ferm i's golden rule, and the energy loss per cycle and unit volum e E of the mode will correspond to this transition rate multiplied by the energy of a phonon $h!_0$ and the period $2 = !_{0}$:

$$E' \frac{2}{!_0} h!_0 \frac{2}{h}n \frac{k_0^2}{p!_0}^2 A_{tot}(!_0)$$
 (8)

where $A_{tot}(!) = P + P_{b} \frac{p}{!_{co}=!}$ is the sum of the resonant and non resonant contributions arising from integrating over the distribution of TLSs, as discussed in the preceding paragraph.

The inverse quality factor $Q^{1}(!_{0})$ is given by $Q^{-1}(!_0) = E = 2 E_0$, where E_0 is the energy stored in the mode per unit volume, E $_{\rm 0}$ ' <code>nh!_0=twL</code> , leading to the following expression at zero tem perature:

$$Q^{1}(!_{0})' 10t^{3=2}w \stackrel{E}{-} b^{1=4} p_{1=0} A_{tot}(!_{0})$$
 (9)

Experiments are done at nite temperatures, and, som e-

out of equilibrium . We take these e ects into account by calculating Atot (!; T) in the presence of a nite distribution of excited vibrations, which can include a non-therm al contribution. If we only keep one phonon processes in the calculation of A $_{\rm tot}$ (!; T), as in the previous discussion, the subtraction of absorption and emission processes cancel the tem perature dependence on the number of phonons. The only tem perature dependence is due to saturation effects in the absorbtion properties of the TLSs when their environm ent contains m any quanta of energy ren. The nalexpression for the inverse quality factor at nite tem peratures is:

$$Q^{1}(!_{0};T)$$
 ' $10t^{3=2}w = \frac{E}{b} \frac{p_{10}}{p_{10}}$
P tanh $\frac{h!_{0}}{k_{B}T} + P_{b} = \frac{r}{!_{00}}$ (10)

Until now prevalence of one-phonon processes in the interaction among TLSs and vibrational modes has been assum ed, but at tem peratures much higher than the frequencies of the relevant phonons, multi-phonon processes need to be taken into account. We include this e ect assuming overdam ped dynamics for the TLSs, so that A (!; ren;T) = $(ren;T)=(1 + [! (ren;T)]^2)$, where ($_{\rm ren}$;T) = $^{-1}$ ($_{\rm ren}$;T), and making use of the relation between Q¹ (!;T) and A (!; ren;T) usually found in the context of the standard tunneling model approach to disordered bulk systems [24{27,38], which in our case translates into:

$$Q^{1}(!;T) = P^{2} = (ET) \int_{0}^{max} d \int_{u_{min}}^{1} du \int_{u_{min}}^{p} \frac{1}{1 u^{2}} = u$$

$$\frac{\cosh^{2} \frac{2}{2T}!}{1 + (!)^{2}}$$
(11)

Here = $p \frac{2}{ren} + \frac{2}{z}$ and u = ren =, with u_m in xed by the time needed to obtain a spectrum around the resonance frequency of the excited mode and m_{ax} estimated to be at least of the order of 5 K [24]. The lim its of integration must be such that only the overdam ped TLSs are included. A given TLS is overdam ped when $[30_{b}^{P}]_{co}^{T}]^{2=3}$. Hence, (_{ren};T) ! ren ren we obtain for the contribution to the inverse quality factor from overdam ped TLSs:

Q¹ (!₀;T)
$$\frac{400P^{2} (_{b}^{p} \overline{!_{co}})^{4=3} T^{1=3}}{E!_{0}}$$
: (12)

Therefore, in a range of energies ! fund !₀ $!_{co}$, the at- $T^{1=3}$ tenuation com ing from these TLSs show sa Q^{-1} (T) dependence, in qualitative agreem ent with the experim ent [18] on Sinanobridges. The total inverse quality factor is the sum of eq.(12) plus the tem perature independent contribution arising from o -resonant processes induced by underdam ped TLSs, eq.(10). This last equation must in



Fig. 4: Fittings of the result of eq.(13) to experim ental data [18].

in the number of underdam ped TLSs as the tem perature is raised, but it is a weak e ect and will be neglected, leading to the nal expression for the total attenuation of a exuralm ode:

$$Q^{1}(!_{0};T) = Q_{0}^{1}(!_{0}) + C(!_{0})T^{1=3};$$
 (13)

where,

$$Q_{0}^{1}(!_{0}) ' \frac{3P_{0}^{4} + 1 = 4}{t^{3} + 2W_{0}E_{0}^{9} = 4} \frac{(1 + 1)(1 - 2)^{1}}{3 + 5} !_{0}^{1} = 2$$

$$C(!_{0}) ' \frac{150P_{0}^{4} + 1 = 3}{t^{2}W_{0}^{4} = 3E_{0}^{4}} \frac{(1 + 1)(1 - 2)^{1}}{3 + 5} \frac{1}{5} (14)$$

A sonly part of the beam is an orphous, P is to be replaced M orphous=Vtotal. To describe the results in [18], by P as shown in g. [4], we assumed P W orphous=Vtotal 10⁴⁴J¹m³, compatible with P values reported in am orphous glasses [24], and $0:1 < V_{am orphous} = V_{total} < 1$. The slope of the $T^{1=3}$ contribution gives the value of , used as thing parameter. We obtain 5 10 eV, which is a reasonable value [39,40]. There are two lim itations on the range of applicability of our results. The increasing role of interactions between TLSs as T is lowered [41], and possible cooperative e ects when the mode is strongly driven [16] cause deviations, which are manifested in the saturation observed in g.(4), not explained by our t, which predicts Q_0^1 5 10. On the high-tem perature side, a point is reached when the rate 1 ($_{ren}$; T) changes to an Arrhenius-like behavior [24].

Conclusions. { We have studied the dam ping of mechanical oscillations in nanoscopic devices due to their interaction with TLSs. This coupling is the main mechanism of relaxation of phonons in disordered insulators. W e principle be corrected by taking into account the decrease have analyzed the changes induced in the spectrum and distribution of TLSs due to their interaction with the low energy oscillations of nano-mechanical devices. F lexural modes, with a high density of states at low energies, lead to sub-ohm ic damping, which can modify signi cantly the distribution of TLSs. The problem of a TLS interacting with a sub-ohm ic environment is interesting in its own right [28,29,36,42{48], and the systems studied here provide a physical realization.

We obtain a tem perature independent contribution to the inverse quality factor, Q¹ of a exural mode, which arises from resonant excitations of TLSs, and o -resonant processes involving underdam ped TLSs. We end, in addition, a contribution which increases as T¹⁼³, arising from overdam ped TLSs. The o -resonant contributions im ply that the externally excited vibration loses its energy to TLSs which, in turn, decay into other acoustic modes. Hence, o -resonant contributions can only be present if the num ber of therm ally excited modes is large, a situation ful lled in most present experiments.

W e have m ade num erical estim ates for the expected dissipation for a few representative devices. W e have assumed that a fraction of the device shows am orphous features, and contains a distribution of TLSs similar to that found in am orphous insulators. The m ain uncertainties in our calculation are due to the lack of inform ation on the TLSs distribution, the coupling strength, and the fraction of the total volume of the device that they occupy. Decreasing volum e and num ber of m odes m ay lead as well to uctuations around our predictions, which use continuum distributions.

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